



General Multilayer Ceramic Capacitors



MLCC is an electronic part that temporarily stores an electrical charge and the most prevalent type of capacitor today. New technologies have enabled the MLCC manufacturers to follow the trend dictated by smaller and smaller electronic devices such as Cellular telephones, Computers, DSC, DVC

General Features

- Miniature Size
- Wide Capacitance and Voltage Range
- Tape & Reel for Surface Mount Assembly
- Low ESR

Applications

- General Electronic Circuit

Part Numbering

CL	<u>10</u>	<u>B</u>	<u> 104</u>	K	<u>B</u>	<u>8</u>	N	N	N	<u>C</u>
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- Samsung Multilayer Ceramic Capacitor
- 2 Size(mm)
- 3 Capacitance Temperature Characteristic
- 4 Nominal Capacitance
- **6** Capacitance Tolerance
- 6 Rated Voltage

- Thickness Option
- Product & Plating Method
- 9 Samsung Control Code
- Reserved For Future Use
- Packaging Type

Samsung Multilayer Ceramic Capacitor

2 SIZE(mm)

Code	EIA CODE	Size(mm)
03	0201	0.6 × 0.3
05	0402	1.0 × 0.5
10	0603	1.6 × 0.8
21	0805	2.0 × 1.25
31	1206	3.2 × 1.6
32	1210	3.2 × 2.5
43	1812	4.5 × 3.2
55	2220	5.7 × 5.0





3 CAPACITANCE TEMPERATURE CHARACTERISTIC

Code		Temperature Characteristics				
С		COG	C△	0 ± 30 (ppm/ °C)		
Р		P2H	P△	-150 ± 60		
R		R2H	R△	-220 ± 60		
S	Class	S2H	S△	-330 ± 60	-55 ~ +125℃	
Т		T2H	T△	-470 ± 60		
U		U2J	U△	-750 ± 60		
L		S2L	S△	+350 ~ -1000		
Α		X5R	X5R	±15%	-55 ~ +85℃	
В	Class II	X7R	X7R	±15%	-55 ~ +125℃	
X	Class II	X6S	X6S	±22%	-55 ~ +105℃	
F		Y5V	Y5V	+22 ~ -82%	-30 ~ +85℃	

***** Temperature Characteristic

Temperature Characteristics	Below 2.0pF	2.2 ~ 3.9pF	Above 4.0pF	Above 10pF
С∆	C0G	C0G	C0G	C0G
Р∆	-	P2J	P2H	P2H
R∆	-	R2J	R2H	R2H
SΔ	-	S2J	S2H	S2H
TΔ	-	T2J	T2H	T2H
UΔ	-	U2J	U2J	U2J

 $J:\pm 120$ PPM/°C, $H:\pm 60$ PPM/°C, $G:\pm 30$ PPM/°C

4 NOMINAL CAPACITANCE

Nominal capacitance is identified by 3 digits.

The first and second digits identify the first and second significant figures of the capacitance.

The third digit identifies the multiplier. 'R' identifies a decimal point.

Example

Code	Nominal Capacitance
1R5	1.5pF
103	10,000pF, 10nF, 0.01 μF
104	100,000pF, 100nF, 0.1 μ F





O CAPACITANCE TOLERANCE

Code	Tolerance	Nominal Capacitance	
Α	±0.05pF		
В	±0.1pF		
С	±0.25pF	Less than 10pF (Including 10pF)	
D	± 0.5pF	(meldaling Topi)	
F	±1pF		
F	±1%		
G	±2%		
J	±5%	Mara than 1075	
K	±10%	More than 10pF	
М	±20%		
z	+80, -20%		

6 RATED VOLTAGE

Code	Rated Voltage	Code	Rated Voltage
R	4.0V	D	200V
Q	6.3V	E	250V
Р	10V	G	500V
О	16V	Н	630V
Α	25V	I	1,000V
L	35V	J	2,000V
В	50V	К	3,000V
С	100V		





THICKNESS OPTION

Size	Code	Thickness(T)	Size	Code	Thickness(T)
0201(0603)	3	0.30±0.03		F	1.25±0.20
0402(1005)	5	0.50±0.05		н	1.6±0.20
0603(1608)	8	0.80±0.10	1812(4532)	I	2.0±0.20
	Α	0.65±0.10		J	2.5±0.20
	С	0.85±0.10		L	3.2±0.30
0805(2012)	F	1.25±0.10		F	1.25±0.20
	Q	1.25±0.15		н	1.6±0.20
	Y	1.25±0.20	2220(5750)	I	2.0±0.20
	С	0.85±0.15		J	2.5±0.20
1206(3216)	F	1.25±0.15		L	3.2±0.30
	Н	1.6±0.20			
	F	1.25±0.20			
	Н	1.6±0.20			
1210(3225)	ı	2.0±0.20			
	J	2.5±0.20			
	v	2.5±0.30			

PRODUCT & PLATING METHOD

Code	Electrode	Termination	Plating Type
Α	Pd	Ag	Sn_100%
N	Ni	Cu	Sn_100%
G	Cu	Cu	Sn_100%

SAMSUNG CONTROL CODE

Code	Description of the code	Code	Description of the code
Α	Array (2-element)	N	Normal
В	Array (4-element)	Р	Automotive
С	High - Q	L	LICC





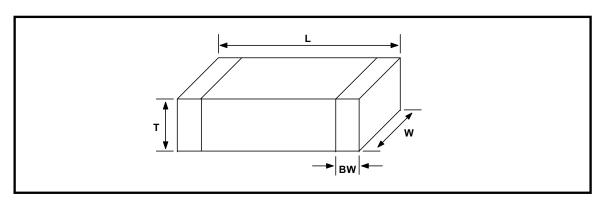
• RESERVED FOR FUTURE USE

Code	Description of the code
N	Reserved for future use

1 PACKAGING TYPE

Code	Packaging Type	Code	Packaging Type
В	Bulk	F	Embossing 13" (10,000EA)
Р	Bulk Case	L	Paper 13" (15,000EA)
С	Paper 7"	0	Paper 10"
D	Paper 13" (10,000EA)	S	Embossing 10"
Е	Embossing 7"		

APPEARANCE AND DIMENSION



CODE	EIA CODE		DIMENSION (mm)							
CODE		L	w	T (MAX)	BW					
03	0201	0.6 ± 0.03	0.3 ± 0.03	0.33	0.15 ± 0.05					
05	0402	1.0 ± 0.05	0.5 ± 0.05	0.55	0.2 +0.15/-0.1					
10	0603	1.6 ± 0.1	0.8 ± 0.1 0.9		0.3 ± 0.2					
21	0805	2.0 ± 0.1	1.25 ± 0.1	1.35	0.5 +0.2/-0.3					
24	4000	3.2 ± 0.15	1.6 ± 0.15	1.40	0.5 +0.2/-0.3					
31	1206	3.2 ± 0.2	1.6 ± 0.2	1.8	0.5 +0.3/-0.3					
20	1210	3.2 ± 0.3	2.5 ± 0.2	2.7	06 + 03					
32	1210	3.2 ± 0.4	2.5 ± 0.3	2.8	0.6 ± 0.3					
43	1812	4.5 ± 0.4	3.2 ± 0.3	3.5	0.8 ± 0.3					
55	2220	5.7 ± 0.4	5.0 ± 0.4	3.5	1.0 ± 0.3					





NO	ITE	М	PER	FORMANCE	TEST	CONDITION		
1	Appea	rance	No Abnormal Exterior	Appearance	Through Microscope(×10)		
2	Insula Resist		10,000MΩ or 500 MΩ·μF Rated Voltage is below 10,000MΩ or 100 MΩ·μF	w 16V ;	Apply the Rated Voltage	For 60 ~ 120	Sec.	
3	Withsta	•	No Dielectric Breakdov Mechanical Breakdown		Class I: 300% of the Rate Class II: 250% of the Rate with less than 50mA curren	d Voltage for 1~5		
					Capacitance	Frequency	Voltage	
		Class	Within the specifie	d tolerance	≤ 1,000 pF	1Mb ±10%		
	I Capacita				>1,000 pF	1kHz ±10%	0.5 ~ 5 Vrms	
4	nce			Capacitance	Frequency	Voltage		
		Class	Within the specifi	ied tolerance	≤ 10 µF	1kHz ±10%	1.0±0.2Vrms	
		П			>10 µF	120 Hz ± 20 %	0.5±0.1Vrms	
			Capacitance ≥ 30pF :	Q ≥ 1,000	Capacitance	Frequency	Voltage	
5	Q Class < 30pF:		: Q ≥ 400 +20C	≤ 1,000 pF	1M½ ±10%			
			(C	: Capacitance)	>1,000 pF	1kHz ±10%	0.5 ~ 5 Vrms	
			1. Characteristic : A(X	X5R), B(X7R), X(X6S)	Capacitance	Frequency	Voltage	
			Rated Voltage	Spec	≤ 10 μF	1kHz ±10%	1.0±0.2Vrms	
			≥ 25V	0.025 max	>10 µF	120 Hz±20%	0.5±0.1Vrms	
			16V	0.035 max	-			
			10V	0.05 max	-			
			6.3V	0.05 max/ 0.10max*1	*1. 0201 C≥0.022uF, 0	402 C≥0.22uF,	0603 C≥2.2uF,	
			2. Characteristic : F(\)	Y5V)	0805 C≥4.7uF, 1206 1812 C≥47uF, 2220 All Low Profile Capa	C≥100uF, acitors (P.16).) C≥22uF,	
6	Tan ∂	Class	Rated Voltage	Spec	*2 0603 C≥0.47uF, 08 *3. 0402 C≥0.033uF, 06			
		П	50V	0.05 max, 0.07max*2	All 0805, 1206 size		F	
			35V	0.07 max	*4 1210 C>6.8uF	, 1210 0 - 0.0u	.	
			25V	0.05 max/ 0.07 max*³/ 0.09max*⁴	*5 0402 C≥0.22uF *6 All 1812 size	0402 C≥0.22uF		
			16V	0.09 max/ 0.125max*5	0 All 1012 3120			
			10V	0.125 max/ 0.16max*6				
			6.3V	0.16max				





NO).TE	NA .		DEDECO	MANCE		TEST CONDITION		
NO	ITE	M 		PERFOR	MANCE		TEST CONDITION		
						· '	shall be measured by the steps		
			Characte	rictics	Temp. Coefficient	shown in the	following table.		
			Characte	HISTICS	(PPM°C)	Step	Temp.(℃)		
			C00	3	0 ± 30	1	25 ± 2		
		Class	PH	1	-150 ± 60	2	Min. operating temp. \pm 2		
		I	RH	1	-220 ± 60	3	25 ± 2		
		1	SH	I	-330 ± 60	4	Max. operating temp \pm 2		
			ТН		-470 ± 60				
			UL		-750 ± 120	5 (4) Class I	25 ± 2		
			SL		+350 ~ -1000	(1) Class I	O#:-:		
	Temperature						Coefficient shall be calculated from		
7	Characteristics					the formula a			
,	of Capacitance					Temp, Coefficie	$nt = \frac{C2 - C1}{C1 \times \triangle T} \times 10^6 \text{ [ppm/°C]}$		
						ance at step 3			
			Charact	n winting	Capacitance Change	C2: Capacita			
			Characte	eristics	with No Bias	△T: 60°C(=8	35℃-25℃)		
		Class	A(X5 B(X7		± 15%	(2) CLASS II			
		1	X(X6	SS)	± 22%	Capacitance (Change shall be calculated from the		
			F(Y5	5V)	+22% ~ -82%	formula as be	elow.		
			ļ .			△C = <u>C2 -</u>	<u>C1</u> × 100(%)		
						C.	1		
							ance at step 3		
						C2: Capacita	ance at step 2 or 4		
						Apply 500g.f * Pressure for 10±1 sec.			
							* 200g.f for 0201 case size.		
	Adhesive	Strenath	No Indicati	ion Of Pee	ling Shall Occur On The				
8	of Term	•	Terminal E		3				
							500g.f		
		I							
		Apperance	No mecha	anical dam	nage shall occur.	Bending limit			
						Test speed ;			
			Charac	teristics	Capacitance Change		board at the limit point in 5 sec.,		
						inen measur	e capacitance.		
					Within \pm 5% or \pm 0.				
			Clas	ss I	5 pF whichever is		20		
	g Bending Strength				larger	<u></u>	R=230		
9				A/VEDV		50			
		Capacitance		A(X5R)/	Mithin + 40 50/				
				B(X7R)/	Within ± 12.5%				
				X(X6S)		│	Par din a limit		
			Class II			45±1	Bending limit 45±1		
				FOVENO	\\/\diship + 200/				
				F(Y5V)	Within ± 30%				
					1				





NO	IT.	ЕМ		PERF	ORMANCE	TEST CONDITION				
			More Than		e terminal surface is to	Solder	Sn-3Ag-0.5	<u> </u>	$\overline{1}$	
			be soldere	d newly, So	metal part does not	Solder	0.1.07.19 0.10	333	\dashv	
			come out	or dissolve		Temp.	245±5℃	235±5℃		
10	Solde	erability		/ T	7/	Flux	R	RMA Type		
			├	′ /	/ //	Dip Time	e 3±0.3 sec	3±0.3 sec. 5±0.5 sec.		
						Pre-heatir	ng at 80~120	°C for 10~30 sec.		
		Apperance	No mechanical damage shall occur.			Solder Ter	mperature: 270	0±5℃		
			Charac	teristics	Capacitance Change		10±1 sec.			
					Within ±2.5% or			fully immersed an	ıd	
			Clas	s I	±0.25 pF whichever is	preheated as below :				
		Capacitance		10/55//	larger	STEP	TEMP.(℃)	TIME(SEC.)		
				A(X5R)/ B(X7R)	Within ±7.5%	1	80~100	60		
			Class II	X(X6S)	Within ±15%	2	150~180	60		
	Resistance to			F	Within ±20%	Leave the	capacitor in ambient condition for			
11	Soldering heat		Capacitance ≥ 30pF : Q≥ 1000			specified time* before measurement				
		Q (Olasa I.)		<30 pF : Q≥ 400+20×C			* 24 ± 2 hours (Class I)			
		(Class I)			(C: Capacitance)	24 ± 2	hours (Class II)		
		Tan δ	Within the	snecified	initial value					
		(Class II)	With the	- opcomod	Timer value					
		Insulation	Within the specified initial value							
		Resistance								
		Withstanding Voltage	Within the specified initial value							
		Appearance	No mecha	anical dam	age shall occur.					
			Charact	eristics	Capacitance Change	1				
					Within ±2.5% or		itor shall be su	-	_	
			Clas	s I	±0.25 pF whichever is	Harmonic Motion having a total amplitude of 1.5mm changing frequency from 10Hz to 55Hz				
		Capacitance			larger		to 10Hz In 1 m	•	/1 12	
				A(X5R)/ B(X7R)	Within ±5%					
12	Vibration		Class	X(X6S)	Within ±10%	Repeat thi	s for 2hours ea	ach in 3 mutually		
	Test			F(Y5V)	Within ±20%	perpendicu	lar directions			
		Q			<u> </u>					
		(Class I)	Within the	specified	initial value					
		Tan δ	Within the	specified	initial value					
		(Class II)	VVIGINI (III	, specified	miliar value					
		Insulation	Within the	snecified	initial value					
		Resistance	VVIGIIII GIE	, specified	inda value					





NO	ITE	M	PERFORMANCE			TEST CONDITION			
		Appearance	No mechanic	cal damage sha	Il occur.	Temperature : 40±2 ℃			
		1,		cteristics	Capacitance Change	Relative humidity : 90~95 %RH			
			Silata		Within ±5.0% or ±0.5pF	Duration time : 500 +12/-0 hr.			
			Cla	ss I	whichever is larger				
		Capacitance		AVVEDV	Wildlever is larger	Leave the capacitor in ambient			
				A(X5R)/ B(X7R)/	\\/\tag{\tag{1.0}}	condition for specified time* before			
			Class	X(X6S)	Within ±12.5%	measurement			
			11	F(Y5V)	Within ±30%	CLASSI : 24±2 Hr.			
			Capacitance ≥ 30pF : Q≥ 350			CLASSII : 24±2 Hr.			
	Humidity	Q	'	•	330 Q≥ 275 + 2.5×C				
13	(Steady	CLASS I			200 + 10×C (C: Capacitance)				
	State)			stic : A(X5R),	2. Characteristic : F(Y5V)				
	,			B(X7R)	(, ,				
			0.05max (16V and over) 0.075max (10V)		0.075max (25V and over)				
		Tan δ			0.1max (16V, C<1.0μF)				
		CLASS II	0.075max	•	0.125max(16V, C≥ 1.0 <i>μ</i> F)				
		OLAGO II	(6.3V excep	t Table 1)	0.15max (10V)				
			0.125max*		0.195max (6.3V)				
			(refer to Tab	le 1)					
		Insulation							
		Resistance	1,000 MΩ or	$50 \text{M}\Omega \cdot \mu \text{F}$ whichever	ver is smaller.				
		Appearance	No mechanic	cal damage sha	Il occur.	Applied Voltage: rated voltage			
			Chara	cteristics	Capacitance Change	Temperature: 40±2 °C			
		Capacitance				Humidity::90~95%RH			
			Class I		Within ±5.0% or ±0.5pF	Duration Time : 500 +12/-0 Hr.			
				ı	whichever is larger	Charge/Discharge Current : 50mA max.			
				A(X5R)/	Within ±12.5%	Perform the initial measurement according to			
				B(X7R)/	Within ±12.5%	Note1.			
			Class II	X(X6S)	Within ±30%				
			Class II		Within ±30%				
				F(Y5V)	M/H-:- 1200/	Perform the final measurement according to			
					Within ±30%	Note2.			
,	Moisture	Q	'	≥30pF : Q≥ 2					
14	Resistance	(Class I)	Capacitance	<30 pF : Q≥ 10	00 + 10/3×C (C: Capacitance)				
			1. Characteri	stic : A(X5R),	2. Characteristic : F(Y5V)				
				B(X7R)					
			0.05max (16\	√ and over)	0.075max (25V and over)				
			0.075max (10	OV)	0.1max (16V, C<1.0 <i>µ</i> F)				
		Tan δ	0.075max		0.125max(16V, C≥ 1.0μ F)				
		(Class II)	(6.3V excep	t Table 1)	0.15max (10V)				
		, ,	0.125max*		0.195max (6.3V)				
			(refer to Tal	ble 1)					
			X(X6S) 0.11n	max (6.3V and b	pelow)				
		Insulation	500 W0	-WO E					
		Resistance	500 MS or 25	5MΩ·μF whicheve	r is smaller.				





NO	ITE	M		PER	FORMANCE		TEST CONDIT	ION		
		Appearance	No mechanio	cal damage	shall occur.	1	oltage: 200%* of the	_		
			Charact	eristics	Capacitance Change		ime: 1000 +48/-0 Hi	·		
				T.	Within ±3% or ±0.3pF,	Charge/Dis	Charge/Discharge Current : 50mA max.			
			Class I		Whichever is larger	* refer to	table(3): 150%/100	% of the rated		
		Capacitance		A(X5R)/ B(X7R)	Within ±12.5%	voltage	table(0) : 100/u 100	70 of the fated		
			Class II	X(X6S)	Within ±25%	Perform th	e initial measurement	according to		
				EA/ELA	Within ±30%	Note1 for	Class II			
				F(Y5V)	Within ±30%					
		0	Capacitance	≥30pF : C	Q ≥ 350	Perform th	e final measurement	according to		
		Q (Class I)	10≤ Capaci	tance <30 p	$F : Q \ge 275 + 2.5 \times C$	Note2.				
	Lliab	(Class 1)	Capacitance	< 10pF :Q	≥ 200 +10×C (C: Capacitance)					
15	High Temperature		1. Characteri							
13	Resistance			B(X7R)						
	Resistance		0.05max		0.075max					
			(16V and o	ver)	(25V and over)					
			0.075max (10	0V)	0.1max(16V, C<1.0μF)					
		Tan ∂	0.075max		0.125max(16V, C≥ 1.0 μ F)					
		(Class II)	(6.3V excep	ot Table 1)	0.15max (10V)					
			0.125max*		0.195max (6.3V)					
			(refer to Ta	ble 1)						
			X(X6S) 0.11	max (6.3V a	nd below)					
		Insulation Resistance	1,000 MΩ or	50MΩ·μF whic	chever is smaller.					
		Appearance	No mechanio	cal damage	shall occur.	Capacitor	shall be subjected	d to 5 cycles.		
			Charact	eristics	Capacitance Change	Condition	for 1 cycle :			
			Class		Within ±2.5% or ±0.25 pF	Step	Temp.(℃)	Time(min.)		
			Oldoc	, 1	Whichever is larger	_ 1	Min. operating	30		
		Capacitance		A(X5R)/	Within ±7.5%	2	temp.+0/-3	2~3		
	Temperature		Class	B(X7R)/ X(X6S)	Within ±15%	-	Max. operating	2-3		
16	Cycle		"	F(Y5V)	Within ±20%	_ 3	temp.+3/-0	30		
		Q		1(130)	**************************************	4	25	2~3		
		(Class I)	Within the s	pecified initia	al value	Leave the	e capacitor in amb			
						-	e capacitor in amb fied time* before m			
		Tan δ	Within the sp	pecified initia	al value			Dagaron Brit		
		(Class II)				_	* 24 ± 2 hours (Class I) 24 ± 2 hours (Class II)			
		Insulation	Within the s	pecified initia	al value	27 1 2	110010 (Old35 II)			
		Resistance								





		Reco	ommended Sold	ering Method		
		Size	Temperature	_	Conc	lition
		inch (mm)	Characteristic	Capacitance	Flow	Reflow
		0201 (0603)	-	-	-	0
		0402 (1005)				
			Class I	-	0	0
		0603 (1608)	Class II	C < 1μF	0	0
	Recommended		Class II	C ≥ 1 <i>μ</i> F	-	0
		0805 (2012)	Class I	-	0	0
18	Soldering Method		Class II	C < 4.7μF	0	0
	By Size & Capacitance		Class II	$C \geq 4.7 \mu F$	-	0
	_,		Array	-	-	0
			Class I	-	0	0
		1206 (3216)	Class II	C < 10μF	0	0
		1200 (3210)	Class II	C ≥ 10 µF	-	0
			Array	-	-	0
		1210 (3225)				0
		1808 (4520)				0
		1812 (4532)	-	-	-	0
		2220 (5750)				0

Note1. Initial Measurement For Class $\ensuremath{\mathbb{I}}$

Perform the heat treatment at 150%+0/-10% for 1 hour. Then Leave the capacitor in ambient condition for 48 ± 4 hours before measurement. Then perform the measurement.

Note2. Latter Measurement

1. CLASS I

Leave the capacitor in ambient condition for 24±2 hours before measurement

Then perform the measurement.

2. Class ${\mathbb I}$

Perform the heat treatment at $150\,^{\circ}\text{C} + 0 /\!\!- 10\,^{\circ}\text{C}$ for 1 hour. Then Leave the capacitor in ambient condition for 48 ± 4 hours before measurement. Then perform the measurement.

*Table1.

Tan ∂	0.125max*
Class Ⅱ A(X5R), B(X7R)	0201 C \geq 0.022 μ F 0402 C \geq 0.22 μ F 0603 C \geq 2.2 μ F 0805 C \geq 4.7 μ F 1206 C \geq 10.0 μ F 1210 C \geq 22.0 μ F 1812 C \geq 47.0 μ F 2220 C \geq 100.0 μ F All Low Profile Capacitors (P.16).

*Table2.

perature Resistance test
± 30%
0402 C ≥ 0.47 μF
0603 C ≥ 2.2μF
0805 C ≥ 4.7μF
1206 C ≥ 10.0 μF
1210 C ≥ 22.0 μF
1812 C ≥ 47.0 <i>μ</i> F
2220 C ≥ 100.0 <i>µ</i> F

*Table3.

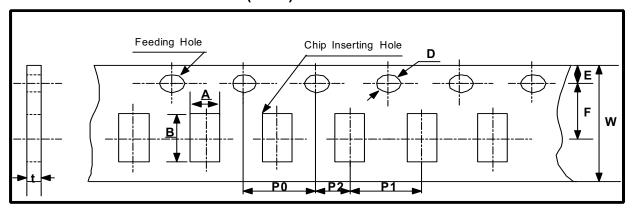
	High Temperature Resistance test									
Applied Voltage	100% of the rated voltage	150% of the rated voltage								
Class II A(X5R), B(X7R), X(X6S), F(Y5V)	0201 C $\geq 0.1 \mu F$ 0402 C $\geq 1.0 \mu F$ 0603 C $\geq 4.7 \mu F$ 0805 C $\geq 22.0 \mu F$ 1206 C $\geq 47.0 \mu F$ 1210 C $\geq 100.0 \mu F$ All Low Profile Capacitors (P.16).	0201 C $\geq 0.022 \mu F$ 0402 C $\geq 0.47 \mu F$ 0603 C $\geq 22 \mu F$ 0805 C $\geq 4.7 \mu F$ 1206 C $\geq 10.0 \mu F$ 1210 C $\geq 22.0 \mu F$ 1812 C $\geq 47.0 \mu F$ 2220 C $\geq 100.0 \mu F$								





PACKAGING

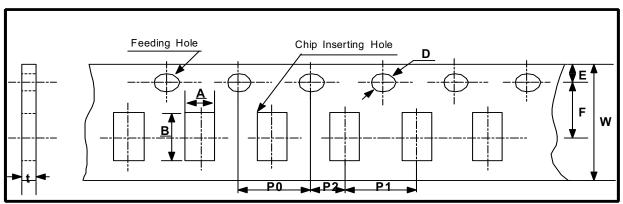
● CARDBOARD PAPER TAPE (4mm)



unit : mm

	mbol ype	Α	В	w	F	E	P1	P2	P0	D	t
D i m	0603 (1608)	1.1 ±0.2	1.9 ±0.2								
e n s	0805 (2012)	1.6 ±0.2	2.4 ±0.2	8.0 ±0.3	3.5 ±0.05	1.75 ±0.1	4.0 ±0.1	2.0 ±0.05	4.0 ±0.1	Ф1.5 +0.1/-0	1.1 Below
i o n	1206 (3216)	2.0 ±0.2	3.6 ±0.2								

● CARDBOARD PAPER TAPE (2mm)



unit: mm

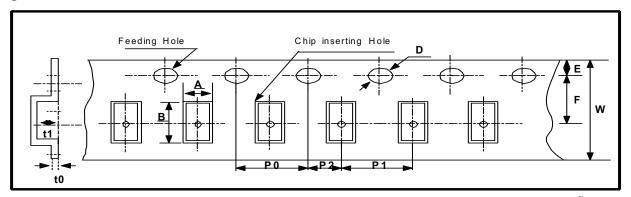
	ymbol Type	A	В	w	F	E	P1	P2	P0	D	t
D i m e	0201 (0603)	0.38 ±0.03	0.68 ±0.03	8.0	3.5	1.75	2.0	2.0	4.0	Ф1.5	0.37 ±0.03
n s i o n	0402 (1005)	0.62 ±0.04	1.12 ±0.04	±0.3	±0.05	±0.1	±0.05	±0.05	±0.1	+0.1/-0.03	0.6 ±0.05





PACKAGING

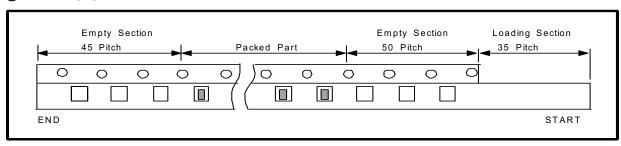
● EMBOSSED PLASTIC TAPE



unit: mm

Sy	m bol	Α	В	w	F	Е	P1	P2	P0	D	t1	t0
Т	уре	, ,			·	_						
	0805 (2012)	1.45 ±0.2	2.3 ±0.2									
D	1206 (3216)	1.9 ±0.2	3.5 ±0.2	8.0 ±0.3	3.5 ±0.05		4.0 ±0.1				2.5 max	
m e	1210 (3225)	2.9 ±0.2	3.7 ±0.2			1.75		2.0	4.0	Ф1.5 +0.1/-0		0.6
n s i	1808 (4520)	2.3 ±0.2	4.9 ±0.2			±0.1		±0.05	±0.1	+0.17-0		Below
o n	1812 (4532)	3.6 ±0.2	4.9 ±0.2	12.0 ±0.3	5.60 ±0.05		8.0 ±0.1				3.8 max	
	2220 (5750)	5.5 ±0.2	6.2 ±0.2									

TAPING SIZE



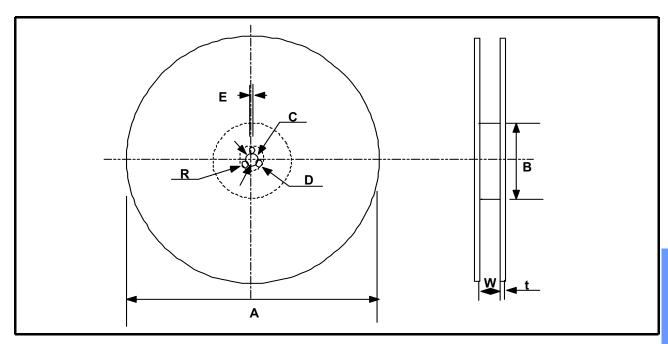
Type	Symbol	Size	Cardboard Paper Tape	Symbol	Size	Embossed Plastic Tape
		0201(0603)	10,000		All Size ≤3216 1210(3225),1808(4520) (t≤1.6mm)	2,000
7" Reel	С	0402(1005)	10,000	E	1210(3225)(t≥2.0mm)	1,000
		OTHERS 4,000		1808(4520)(t≥2.0mm)	1,000	
10" Reel	0	-	10,000	-	-	-
	D	0402(1005)	50,000		All Size ≤3216 1210(3225),1808(4520) (t<1.6mm)	10,000
		OTHERS	10,000		$1210(3225)(1.6 \le t < 2.0 \text{ m m})$ $1206(3216)(1.6 \le t)$	8,000
13" Reel		0603(1608)	10,000 or 15,000	F	$1210(3225),1808(4520) $ $(t \ge 2.0 \text{mm})$	4,000
	L 0805(2012) 15,000 or (t<0.85mm) 10,000(Option)	L 0805(2012) 15,000 or (t≤0.85mm) 10,000(Option)		1812(4532)(t≤2.0 m m)	4,000	
		1206(3216) (t≤0.85mm)	10,000		1812(4532)(t>2.0mm) 5750(2220)	2,000





PACKAGING

• REEL DIMENSION



unit : mm

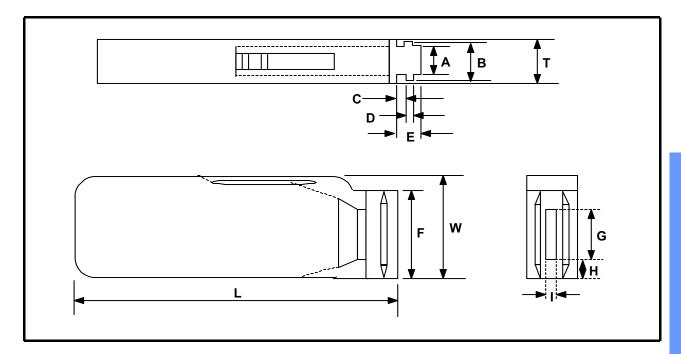
Symbol	Α	В	С	D	E	W	t	R
7" Reel	ф180+0/ -3	ф60+1/ -3	442 0.2	25 0.5	20105	0.14.5	1.2±0.2	4.0
13" Reel	ф330±2.0	ф80+1/ -3	φ13±0.3	25±0.5	2.0±0.5	9±1.5	2.2±0.2	1.0





BULK CASE PACKAGING

- Bulk case packaging can reduce the stock space and transportation costs.
- The bulk feeding system can increase the productivity.
- It can eliminate the components loss.



unit: mm

Symbol	Α	В	Т	С	D	E
Dimension	6.8±0.1	8.8±0.1	12±0.1	1.5+0.1/-0	2+0/-0.1	3.0+0.2/-0

Symbol	F	W	G	Н	L	I
Dimension	31.5+0.2/-0	36+0/-0.2	19±0.35	7±0.35	110±0.7	5±0.35

QUANTITY OF BULK CASE PACKAGING

unit : pcs

C:=o	0402/4005)	0602(4609)	0805(2012)		
Size	0402(1005)	0603(1608)	T=0.65mm	T=0.85mm	
Quantity	50,000	10,000 or 15,000	10,000	5,000 or 10,000	

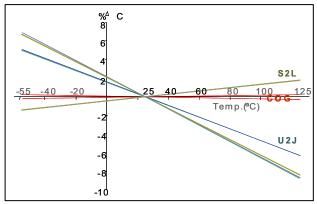


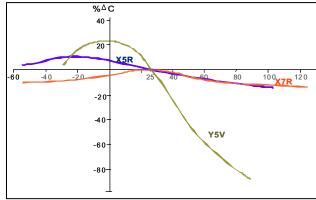


APPLICATION MANUAL

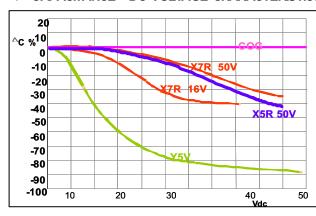
ELECTRICAL CHARACTERISTICS

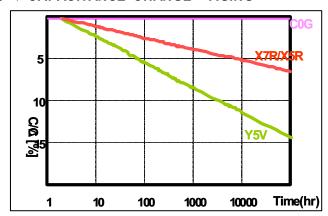
► CAPACITANCE - TEMPERATURE CHARACTERISTICS



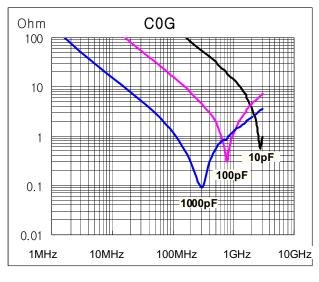


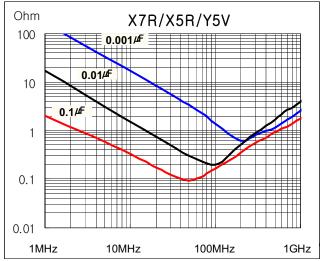
► CAPACITANCE - DC VOLTAGE CHARACTERISTICS ► CAPACITANCE CHANGE - AGING





▶ IMPEDANCE - FREQUENCY CHARACTERISTICS









STORAGE CONDITION

▶ Storage Environment

The electrical characteristics of MLCCs were degraded by the environment of high temperature or humidity. Therefore, the MLCCs shall be stored in the ambient temperature and the relative humidity of less than 40°C and 70%, respectively.

Guaranteed storage period is within 6 months from the outgoing date of delivery.

▶ Corrosive Gases

Since the solderability of the end termination in MLCC was degraded by a chemical atmosphere such as chlorine, acid or sulfide gases, MLCCs must be avoid from these gases.

▶ Temperature Fluctuations

Since dew condensation may occur by the differences in temperature when the MLCCs are taken out of storage, it is important to maintain the temperature-controlled environment.

DESIGN OF LAND PATTERN

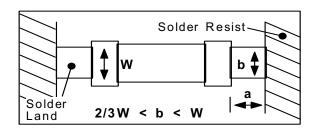
When designing printed circuit boards, the shape and size of the lands must allow for the proper amount of solder on the capacitor.

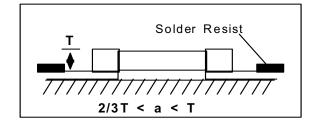
The amount of solder at the end terminations has a direct effect on the crack.

The crack in MLCC will be easily occurred by the tensile stress which was due to too much amount of solder. In contrast, if too little solder is applied, the termination strength will be insufficiently.

Use the following illustrations as guidelines for proper land design.

Recommendation of Land Shape and Size.









ADHESIVES

When flow soldering the MLCCs, apply the adhesive in accordance with the following conditions.

► Requirements for Adhesives

They must have enough adhesion, so that, the chips will not fall off or move during the handling of the circuit board.

They must maintain their adhesive strength when exposed to soldering temperature.

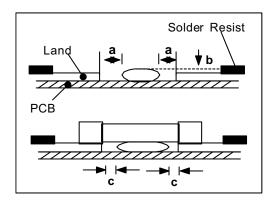
They should not spread or run when applied to the circuit board.

They should harden quickly. They should not corrode the circuit board or chip material.

They should be a good insulator. They should be non-toxic, and not produce harmful gases, nor be harmful when touched.

► Application Method

It is important to use the proper amount of adhesive. Too little and much adhesive will cause poor adhesion and overflow into the land, respectively.



		unit : mm
Туре	21	31
а	0.2 min	0.2 min
b	70~100 µm	70~100 µm
С	> 0	> 0

Adhesive hardening Characteristics

To prevent oxidation of the terminations, the adhesive must harden at 160 ℃ or less, within 2 minutes or less.

MOUNTING

Mounting Head Pressure

Excessive pressure will cause crack to MLCCs. The pressure of nozzle will be 300g maximum during mounting.

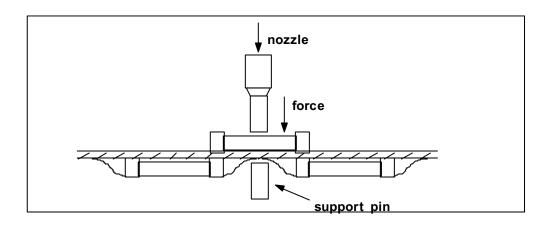




Bending Stress

When double-sided circuit boards are used, MLCCs first are mounted and soldered onto one side of the board. When the MLCCs are mounted onto the other side,

it is important to support the board as shown in the illustration. If the circuit board is not supported, the crack occur to the ready-installed MLCCs by the bending stress.



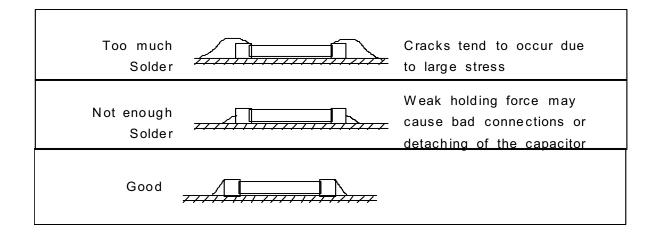
Manual Soldering

Manual soldering can pose a great risk of creating thermal cracks in chip capacitors.

The hot soldering iron tip comes into direct contact with the end terminations, and operator's carelessness may cause the tip of the soldering iron to come into direct contact with the ceramic body of the capacitor.

Therefore the soldering iron must be handled carefully, and close attention must be paid to the selection of the soldering iron tip and to temperature control of the tip.

Amount of Solder







▶ Cooling

Natural cooling using air is recommended. If the chips are dipped into solvent for cleaning, the temperature difference($\triangle T$) must be less than 100 $^{\circ}$ C

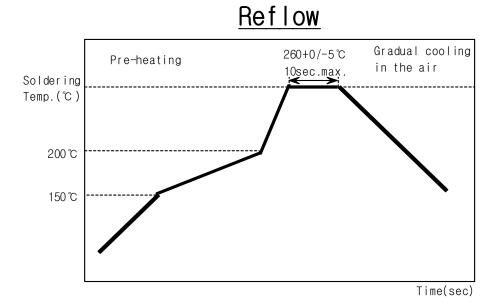
Cleaning

If rosin flux is used, cleaning usually is unnecessary. When strongly activated flux is used, chlorine in the flux may dissolve into some types of cleaning fluids, thereby affecting the chip capacitors. This means that the cleaning fluid must be carefully selected, and should always be new.

▶ Notes for Separating Multiple, Shared PC Boards.

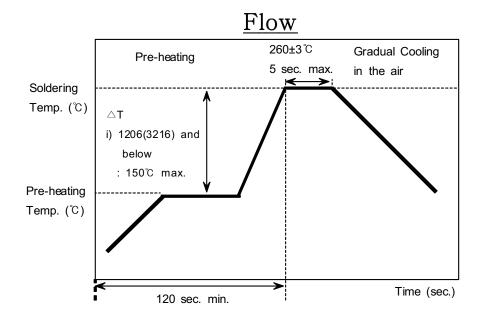
A multi-PC board is separated into many individual circuit boards after soldering has been completed. If the board is bent or distorted at the time of separation, cracks may occur in the chip capacitors. Carefully choose a separation method that minimizes the bending often circuit board.

▶ Recommended Soldering Profile









Soldering Iron

Variation of Temp.	Soldering	Pre-heating	Soldering	Cooling
	Temp (°C)	Time (Sec)	Time(Sec)	Time(Sec)
△T≤130	300±10℃max	≥ 60	≤ 4	-

Condition of Iron facilities				
Wattage	Tip Diameter	Soldering Time		
20W Max	3mm Max	4 Sec Max		

^{*} Caution - Iron Tip Should Not Contact With Ceramic Body Directly.